

February 2002

The MACH[®] families are manufactured using Lattice's advanced electrically-erasable (EE) CMOS process. This technology uses an EE cell to replace the fuse link used in bipolar parts. As a result, the device can be erased and reprogrammed, a feature which allows 100% testing at the factory.

Parameter Symbol	Parameter Description	Value	Unit	Test Conditions
t_{DR}	Min Pattern Data Retention Time	20	Years	Max Operating Temperature
		10	Years	Max Storage Temperature
N	Max Reprogramming Cycles	100	Cycles	Normal Programming Conditions

Input/Output Equivalent Schematics

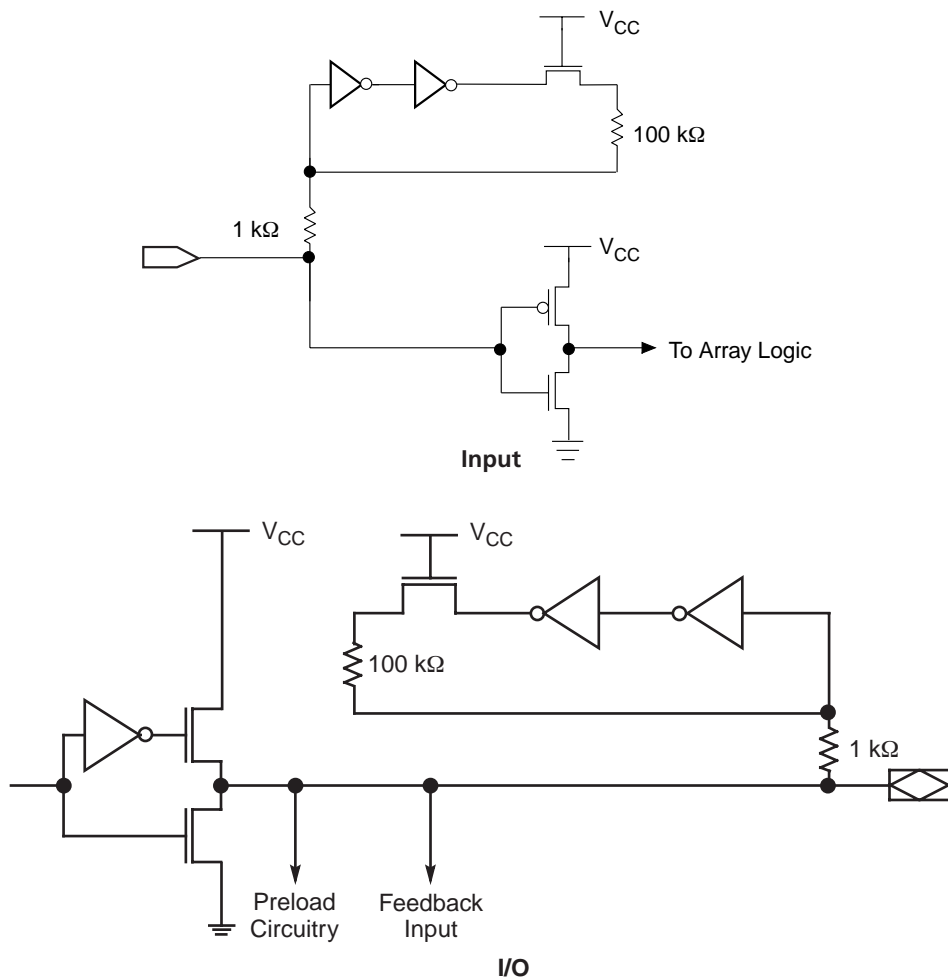


Figure 1. Bus-Friendly™ Latch

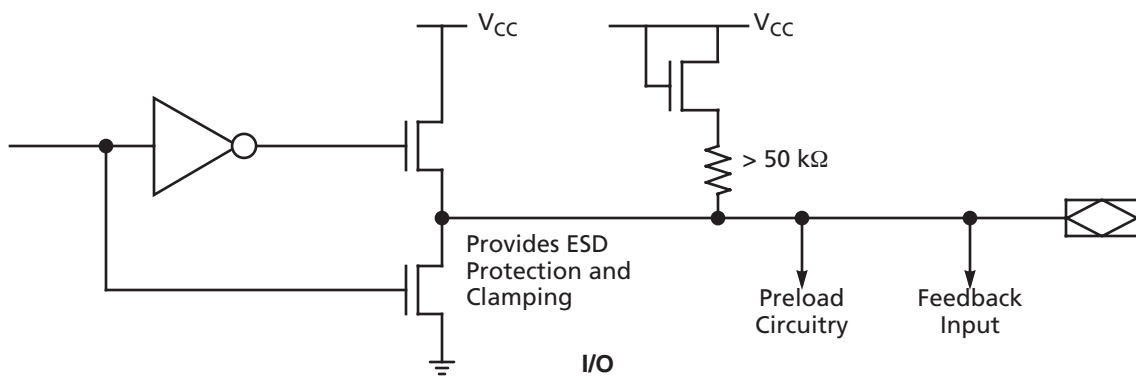
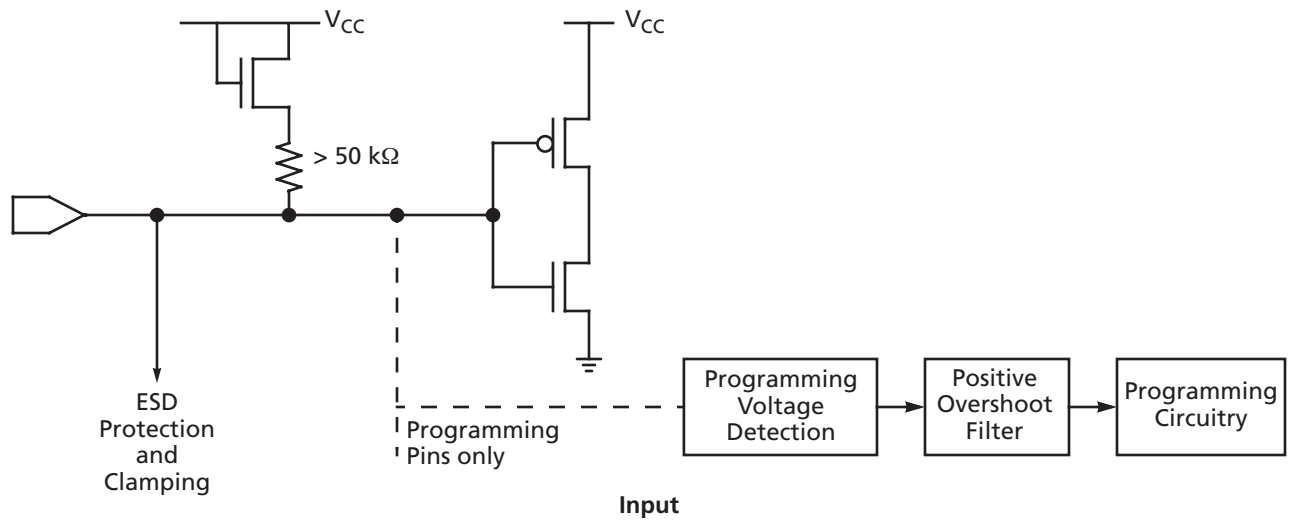


Figure 2. Pull-up Resistor